

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/708,836	BEENAU ET AL.	
Examiner	Art Unit	
Nam V. Nguyen	2635	

SEARCHED					
Class	Subclass	Date	Examiner		
340	5.53	11/29/2005	NN		
340	5.2	11/29/2005	NN		
340	5.4+	11/29/2005	NN		
340	5.52	11/29/2005	NN		
340	5.6	11/29/2005	NN		
340	5.8+	11/29/2005	NN		
340	10.1	11/29/2005	NN		
340	10.4-10.5	11/29/2005	NN		
235	379	11/29/2005	NN		
235	380	11/29/2005	NN		
235	492	11/29/2005	NN		
705	35,54,76	11/29/2005	NN		
705	186,194	11/29/2005	NN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
East Search: USPAT; US-PUB; EPO;JPO; and Derwent.	11/29/2005	NN
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